

<b>Notice of References Cited</b>	Application/Control No. 10/028,039	Applicant(s)/Patent Under Reexamination THATCHER ET AL.	
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	B	US-6418387	01-1999	Carney	702/81
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

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	U	Niggemeyer et al., Parametric Built-In-Self-Test of VLSI Systems, January 1999, University of Hannover, pages 1-5.
	V	Hamada et al., A High-speed Boundary Search by Shmoo Plot for ULSI Memories, Janary 1993, IEEE, Vol: 4150, pages 4-9.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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